

<b>Notice of References Cited</b>	Application/Control No. 10/510,400		Applicant(s)/Patent Under Reexamination SHIONO ET AL.	
	Examiner Henok G. Heyi		Art Unit 2627	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-5,698,344 A	12-1997	Bai et al.	430/1
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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